

# STP80NF10FP-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)			
100	0.0085 at V <sub>GS</sub> = 10 V	90			
100	0.0100 at V <sub>GS</sub> = 6 V	85			

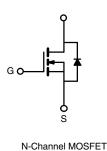
#### **FEATURES**

- Trench Power MOSFET
- 175 °C Maximum Junction Temperature
- Compliant to RoHS Directive 2002/95/EC









ABSOLUTE MAXIMUM RATI	NGS T <sub>A</sub> = 25 °C, unless other	erwise noted		
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	± 20	V	
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	T <sub>C</sub> = 25 °C	I <sub>D</sub>	90	
Continuous Diain Current (1) = 150 °C)	T <sub>C</sub> = 125 °C	- O	70 <sup>a</sup>	٨
Pulsed Drain Current		I <sub>DM</sub>	287	Α
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	75	
Single Pulse Avalanche Energy <sup>b</sup>	L = 0.1 IIII	E <sub>AS</sub>	280	mJ
	T <sub>C</sub> = 25 °C (TO-220F)	P <sub>D</sub>	56	W
Maximum Power Dissipation <sup>b</sup>	T <sub>A</sub> = 25 °C (TO-220F)		3.75	
Operating Junction and Storage Temperatu	re Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-220) d	R <sub>thJA</sub>	40			
Junction-to-Ambient	Free Air (TO-220)	' 'thJA	62.5	°C/W		
Junction-to-Case		R <sub>thJC</sub>	0.6			

#### Notes

- a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS}$ $V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$ 100				V	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1		3	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			50	μΑ	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 175 °C			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.0085			
		V <sub>GS</sub> = 6 V, I <sub>D</sub> = 20 A		0.0100		1 _	
Drain-Source On-State Resistance <sup>a</sup>	H <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 125 °C		0.0160		Ω	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 175 °C		0.0210			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			6550		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1 MHz		665			
Reverse Transfer Capacitance	C <sub>rss</sub>	1		265			
Total Gate Charge <sup>c</sup>	$Q_g$			105			
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$		17		nC	
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$	1		23			
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			12	25		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_{L} = 0.6 \Omega$		90	135	ns	
Turn-Off DelayTime <sup>c</sup>	t <sub>d(off)</sub>	$I_D\cong 85$ A, $V_{GEN}=10$ V, $R_g=2.5~\Omega$		55	85		
Fall Time <sup>c</sup>	t <sub>f</sub>	1		130	195	1	
Source-Drain Diode Ratings and Cha	racteristics T <sub>C</sub>	= 25 °C <sup>b</sup>					
Continuous Current	I <sub>S</sub>			90		_	
Pulsed Current	I <sub>SM</sub>			240		Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 85 A, V <sub>GS</sub> = 0 V		1.0	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			85	140	ns	
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, dI/dt = 100 A/μs		4.5	7	Α	
Reverse Recovery Charge	Q <sub>rr</sub>	1		0.17	0.35	μC	

#### Notes:

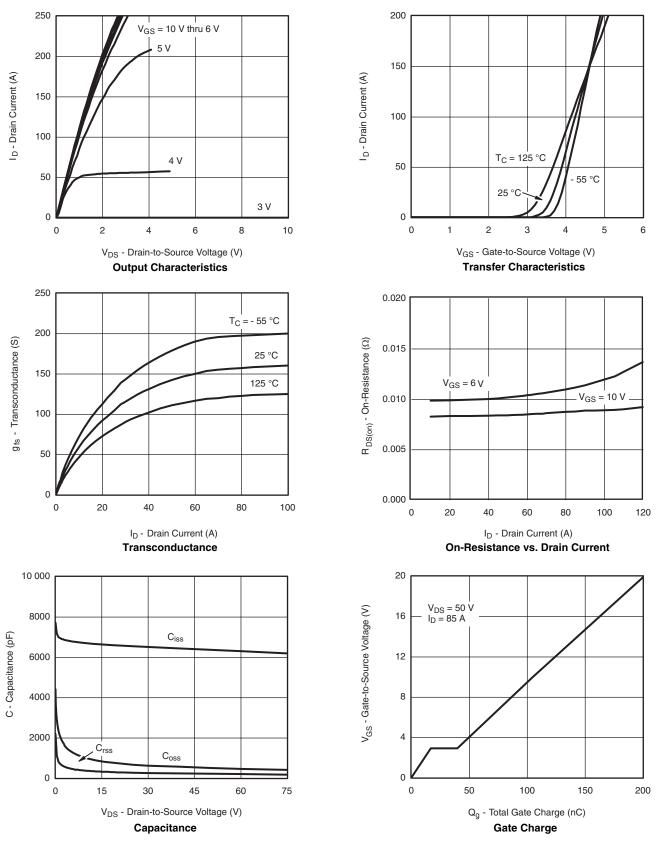
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- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

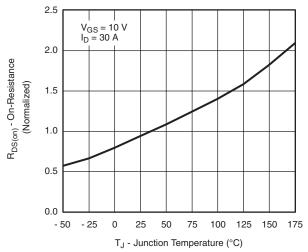


**TYPICAL CHARACTERISTICS**  $T_A = 25 \, ^{\circ}C$ , unless otherwise noted

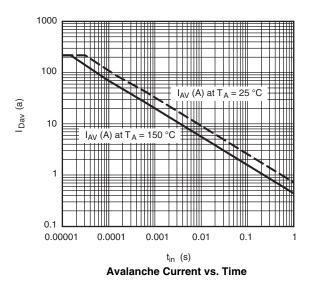




# **TYPICAL CHARACTERISTICS** $T_A = 25 \, ^{\circ}C$ , unless otherwise noted



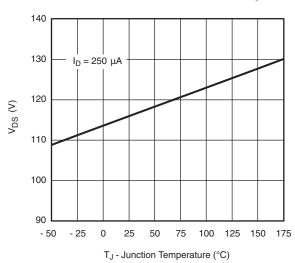
#### On-Resistance vs. Junction Temperature



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T<sub>J</sub> = 150 °C T<sub>J</sub> = 25 °C T<sub>J</sub>

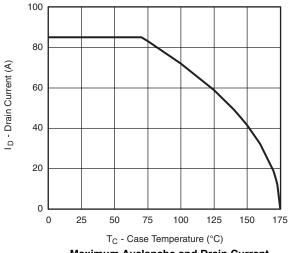
Source-Drain Diode Forward Voltage

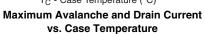


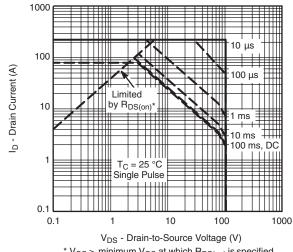
T<sub>J</sub> - Drain-Source Breakdown vs. Junction-Temperature



#### **THERMAL RATINGS**

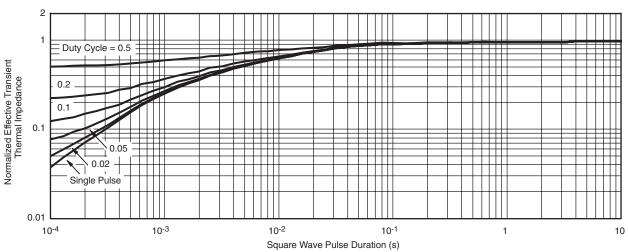






\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area



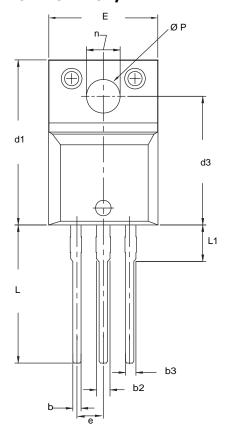
Normalized Thermal Transient Impedance, Junction-to-Case

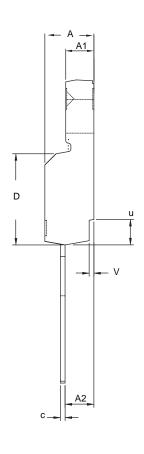
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## **TO-220 FULLPAK (HIGH VOLTAGE)**





DIM.	MILLIN	METERS	INC	HES
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
Е	10.360	10.630	0.408	0.419
е	2.54 BSC		0.100 BSC	) BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

# DWG: 5972

## Notes

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.
   No chipping or package damage.



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